



<p>Searched</p> 	<p>Application/Control No.</p> <p>10603787</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>LEE ET AL.</p>
	<p>Examiner</p> <p>Kowalewski, Filip A</p>	<p>Art Unit</p> <p>3736</p>

Class	SubClass	Date	Examiner
600	300-301	6/30/2006	FAK
128	903-905	6/30/2006	FAK
434	236-238	6/30/2006	FAK

U.S. Patent and Trademark Office	Part of Paper No.:
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Search Notes 	Application/Control No. 10603787	Applicant(s)/Patent Under Reexamination LEE ET AL.
	Examiner Kowalewski, Filip A	Art Unit 3736

Notes	Date	Examiner
Plus search	6/30/2006	FAK
IDS search	6/29/2006	FAK
East Keyword search	6/29/200 - 6/30/2006	FAK
Inventor Search	6/29/2006	FAK
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